# Tracking with silicon detector 

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## Outline

1. What is a silicon tracking system
2. Track parameters and resolutions
3. Silicon detectors
4. Tracking systems
5. Understanding track fitting (optional)
6. Performance and applications

WHAT IS A (SILICON) TRACKING SYSTEM?


Reconstruction of charged particles produced in particle physics experiments: with high granularity with high precision: position down to $\mathrm{O}(10 \mu \mathrm{~m})$ momentum down to $10^{-3}$
Unique way to access the region of the interaction vertex (pileup, short lived particles)


## A particle physics detector

Momentum measurement, Production and decay vertex reconstruction, hadron identification. Light material ( $\sim 1 \mathbf{X}_{\mathbf{0}}$ )


## Evolution of tracking systems



1) $B_{1}^{0} \rightarrow D_{1}^{*-} \mu_{1}^{+} v_{1}, D_{1}^{*-} \rightarrow \pi_{1}^{-} \bar{D}, \bar{D} \xrightarrow{0} K_{1}^{+} \pi_{1}^{-}$
2) $B_{2}^{0} \rightarrow D_{2}^{*}-\mu_{2}^{+} \nu_{2}, D_{2}^{*-} \rightarrow \pi^{0} D^{-}, D^{-} \rightarrow K_{2}^{+} \pi_{2}^{-} \pi_{2}^{-}$
...through the addition of few very precise Si-based measurements near to the interaction region...

From continuous tracking with gas detector...


## Evolution of tracking systems

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CMS

CMS Experiment at LHC CERN Data recorded: Sun Jul 4 01:33:41 2010 EDT mi section: 20
umi section: 20
$\mathrm{B}_{\mathrm{s}} \rightarrow J / \psi \phi \quad$ candidate eve

- A lot of the contents of today slides is taken from:
- F. Ragusa, New Journal of Physics 9 (2007) 336
- The lectures given at the CERN EDIT 2011 School (especially by P. Wells) http://edit2011.web.cern.ch/edit2011
- C. Haber's lectures at the TIPP 2011 conference http://conferences.fnal.gov/tipp11
- Books
- Kleinknecht, Detectors for Particle Radiation, Cambridge University Press
- Fernow, Introduction to experimental particle physics, Cambridge University Press
- Regler, Data analysis techniques for high-energy physics experiments, Cambridge University Press


## THE TRACK MODEL

Do not try to follow all formulas during the lecture...they are there just for reference

## Superconducting solenoids

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- The Lorentz force does not change the energy of a particle

$$
\frac{d \mathbf{p}}{d t}=e \mathbf{v} \times \mathbf{B}
$$

- since we measure a trajectory, we explicit the position vector $\mathbf{r}$ :

$$
\begin{aligned}
& m \gamma \frac{d \mathbf{v}}{d t}=e \mathbf{v} \times \mathbf{B} \\
& m \gamma \frac{d^{2} \mathbf{r}}{d t^{2}}=e \frac{d \mathbf{r}}{d t} \times \mathbf{B}
\end{aligned}
$$

- and, since v is constant, can use the path length $s=\mathrm{v} t$ :

$$
\begin{gathered}
d s=\mathrm{v} d t \\
m \gamma \mathrm{v} \frac{d^{2} \mathbf{r}}{d s^{2}}=e \frac{d \mathbf{r}}{d s} \times \mathbf{B}
\end{gathered}
$$

- finally:

$$
\frac{d^{2} \mathbf{r}}{d s^{2}}=\frac{e}{p} \frac{d \mathbf{r}}{d s} \times \mathbf{B}
$$

- If the $\mathbf{B}$ field is homogeneous the trajectory in a helix:

- In the more general case of inhomogeneous magnetic field, $\mathbf{B}(\mathrm{s})$ varies along the trajectory $\mathbf{r}(\mathrm{s})$, and the differential equation needs to be solved numerically.


## A CMS slice



## The helix equation

- The helix is described in parametric form:

$$
\begin{aligned}
& x(s)=x_{0}+R\left[\cos \left(\Phi_{0}+\frac{h s \cos \lambda}{R}\right)-\cos \Phi_{0}\right] \\
& y(s)=y_{0}+R\left[\sin \left(\Phi_{0}+\frac{h s \cos \lambda}{R}\right)-\sin \Phi_{0}\right] \\
& z(s)=z_{0}+s \sin \lambda
\end{aligned}
$$

- $\lambda$ is the dip-angle
- $h= \pm 1$ is the sense of rotation (sign of the charge)
- The projection on the $x-y$ plane is a circle:

$$
\left(x-x_{0}+R \cos \Phi_{0}\right)^{2}+\left(y-y_{0}+R \sin \Phi_{0}\right)^{2}=R^{2}
$$

- $x_{0}$ and $y_{0}$ are the coordinates at $s=0$
- $\Phi_{0}$ is also related to the slope of the tangent of the circle at $s=0$


## Perigee parameters

In the helix equation:

- The $s=0$ point is an arbitrary choice
- A common use case is when the track is reconstructed in a region of size $\ll \boldsymbol{R}$
- $p_{\mathrm{T}}=1 \mathrm{GeV}, B=2 \mathrm{~T}, R=1.7 \mathrm{~m}$
- radius of ATLAS traking system is 1.05 m

$$
p_{\mathrm{T}}[\mathrm{GeV}]=0.3 B[\mathrm{~T}] R[\mathrm{~m}]
$$

- ...or if interested in the proximity of the interaction region
- Choose as reference point the perigee: the closest point to the origin of the reference frame (i.e. detector center)
- Write as a Taylor expansion in $s / R$
- this is an approximation!
- error $\mathrm{O}\left(s^{3} / R^{2}\right)$
- but it will be very useful for future examples



## Perigee parameters

- Development in $\mathrm{s} / \mathrm{R}$ :
$x(s)=x_{0}-h s \cos \lambda \sin \Phi_{0}-\frac{1}{2} \frac{s^{2} \cos ^{2} \lambda}{R} \cos \Phi_{0}$
$y(s)=y_{0}+h s \cos \lambda \cos \Phi_{0}-\frac{1}{2} \frac{s^{2} \cos ^{2} \lambda}{R} \sin \Phi_{0}$
$z(s)=z_{0}+s \sin \lambda$
- we can now introduce the perigee parameters:

$$
\begin{aligned}
& x(s)=-d_{0} \sin \varphi_{0}+s \sin \vartheta \cos \varphi_{0}+\frac{1}{2} \kappa s^{2} \sin ^{2} \vartheta \sin \varphi_{0} \\
& y(s)=d_{0} \cos \varphi_{0}+s \sin \vartheta \sin \varphi_{0}-\frac{1}{2} \kappa s^{2} \sin ^{2} \vartheta \cos \varphi_{0} \\
& z(s)=z_{0}+s \cos \vartheta
\end{aligned}
$$

- impact parameter $\mathrm{d}_{0}$ :
$x_{0}=d_{0} h \cos \Phi_{0}, \quad y_{0}=d_{0} h \sin \Phi_{0}$
notice it has a sign!
- the direction of the track at the perigee $\varphi_{0}$ :

$$
\cos \varphi_{0}=h \sin \Phi_{0}, \quad \sin \varphi_{0}=-h \cos \Phi_{0}
$$

- the curvature $\kappa=\frac{h}{R}$
which includes the sign of the charge

- and the polar angle $\vartheta=\frac{\pi}{2}-\lambda$


## High- $p_{\tau}$ parabolic approximation

- Starting from the parametric trajectory

$$
\begin{aligned}
& x(s)=-d_{0} \sin \varphi_{0}+s \sin \vartheta \cos \varphi_{0}+\frac{1}{2} \kappa s^{2} \sin ^{2} \vartheta \sin \varphi_{0} \\
& y(s)=d_{0} \cos \varphi_{0}+s \sin \vartheta \sin \varphi_{0}-\frac{1}{2} \kappa s^{2} \sin ^{2} \vartheta \cos \varphi_{0} \\
& z(s)=z_{0}+s \cos \vartheta
\end{aligned}
$$

- It is now interesting to define a change of coordinates $x, y \rightarrow x^{\prime}, y^{\prime}$, with the $x^{\prime}$-axis directed along the track direction:

$$
\begin{aligned}
x^{\prime} & =x \cos \phi_{0}+y \sin \phi_{0} \\
y^{\prime} & =-x \sin \phi_{0}+y \cos \phi_{0}
\end{aligned} \begin{array}{ll}
x^{\prime}(s) & =s \sin \vartheta \\
y^{\prime}(s) & =d_{0}-\frac{1}{2} \kappa s^{2} \sin ^{2} \vartheta \\
z(s) & =z_{0}+s \cos \vartheta
\end{array}
$$

- In these coordinates the trajectory has a simple expression in the longitudinal $\rho-z$ and transverse $\rho, y^{\prime}$ planes:

$$
\begin{aligned}
& z=z_{0}+x^{\prime} \tan \vartheta \\
& y^{\prime}=d_{0}-\frac{1}{2} \kappa x^{\prime 2}
\end{aligned}
$$

- Sometimes $r=\sqrt{ }\left(x^{2}+y^{2}\right)$ is used instead of $x^{\prime}$ :
- this is a "double" approximation valid for $r \gg d_{0}$
- If rotating to an axis near to the particle direction (the jet-axis for example)

$$
y^{\prime}=d_{0}+x^{\prime} \tan \left(\phi_{0}-\phi_{\mathrm{jet}}\right)-\frac{1}{2} \kappa x^{\prime 2}
$$

## Impact parameter resolution

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- In proximity of the production vertex, one can ignore the $\kappa x^{\prime 2}$ term and consider the trajectory a straight line.
- Let's take two detector planes:
- at positions $\mathbf{x}_{1}$ and $\mathbf{x}_{2}$,
- resolution $\sigma_{\mathbf{y}}$ on the $\mathbf{y}$-coordinate measurement.
- The reconstructed trajectory is:

$$
y=\frac{y_{2}-y_{1}}{x_{2}-x_{1}} x+\frac{y_{1} x_{2}-y_{2} x_{1}}{x_{2}-x_{1}}
$$

- The uncertainty on the impact parameter is:

$$
\begin{aligned}
\sigma_{d} & =\frac{\sqrt{x_{2}^{2}+x_{1}^{2}}}{x_{2}-x_{1}} \\
& =\sqrt{\frac{n^{2}+1}{(n-1)^{2}}} \sigma_{y}
\end{aligned}
$$

- where we introduced the lever arm: $\mathbf{n}=\mathbf{x}_{2} / \mathbf{x}_{1}$


## Impact parameter resolution (2)

- Multiple scattering play a key role in the impact parameter resolution.
- Each material layer crossed by the particle before reaching the detector, deflects the particle by a random angle with r.m.s.:

$$
\theta_{0}=\frac{13.6 \mathrm{MeV}}{\beta c p} z \sqrt{\frac{l}{X_{0}}}\left(1+0.038 \ln \frac{l}{X_{0}}\right)
$$

where $\boldsymbol{l}$ is the thickness of the crossed material.

- This deflection translate in an error on the impact parameter of

$$
\delta d=R \cdot \theta_{0}
$$

where $\boldsymbol{R}$ is the distance of the material layer from the interaction point.

- Summing in quadrature all contributions:

$$
\sigma_{d}=\sqrt{\sum_{i} R_{i}^{2} \theta_{0, i}^{2}}
$$



- The sum is computed over all material layers till the first measured point (included).
- The formula for $\boldsymbol{\theta}_{\mathbf{0}}$ is valid in a plane perpendicular to the trajectory. If the track is tilted by an angle $\boldsymbol{\vartheta}$ with respect to the $x-y$ plane, the projected angle is magnified by a factor $\mathbf{1 / s i n} \boldsymbol{\vartheta}$.
- Also the crossed thickness $\boldsymbol{l}$ increases in the same way, providing an additional $\mathbf{1} / \boldsymbol{\operatorname { s i n }}^{\mathbf{1 / 2}} \boldsymbol{\vartheta}$ factor.
- Momentum is measured from the bending of the trajectory.
- In collider experiments detectors are put inside the magnetic field.
- Measuring the sagitta $s$ over a length $L$ :

$$
\begin{aligned}
& s=R\left(1-\cos \frac{\theta}{2}\right) \approx R \frac{\theta^{2}}{8} \\
& =\frac{q B L^{2}}{8 p}
\end{aligned}
$$

- numerically:

$$
s[\mathrm{~m}]=\frac{0.3 B[\mathrm{~T}] L^{2}[\mathrm{~m}]}{8 p[\mathrm{GeV} / \mathrm{c}]}
$$

- If measurement by only three detectors:

$$
\begin{aligned}
& s=y_{2}-\frac{1}{2}\left(y_{1}+y_{3}\right) \\
& \sigma_{s}=\sqrt{3 / 2} \sigma_{y}
\end{aligned}
$$

- Momentum resolution is

$$
\frac{\sigma_{p}}{p}=\frac{\sigma_{s}}{s}=\frac{\sqrt{3 / 2} \sigma_{y} 8 p}{0.3 B L^{2}}
$$



- For multiple scattering deflections in the detector material:
$\delta y_{2}=\frac{L}{2} \delta \theta_{1} \quad \delta y_{3}=L \delta \theta_{1}+\frac{L}{2} \delta \theta_{2} \quad \Rightarrow \quad \delta s=\delta y_{2}-\frac{1}{2} \delta y_{3}=-\frac{L}{2} \delta \theta_{2} \quad \sigma_{s}=\frac{L}{2} \theta_{\mathrm{ms}, 2}$
- This is a multiple scatterring contribution to the curvature measurement.
- Adding the two terms, we get:

$$
\sigma_{s}=\sigma_{\mathrm{tracking}} \oplus \frac{\sigma_{\mathrm{MS}}}{p}
$$

- The relative momentum resolution becomes:

$$
\frac{\sigma_{p}}{p}=\frac{\sigma_{s}}{s}=\frac{8}{0.3 B L^{2}}\left(p \sigma_{\text {tracking }} \oplus \sigma_{\mathrm{MS}}\right)
$$

- resolution improves linearly with $\boldsymbol{B}$ and with the detector point resolution
- the improvement is quadratic in $\boldsymbol{L}$
- relative momentum resolution:
- is constant at low momentum (MS)
- worsens with increasing momentum



## Performance requirements



- Very interesting in current experiments are the heavy flavours $(c, b, \tau)$.
- lifetime of $\mathrm{O}\left(10^{-12} \mathrm{~s}\right)$
- impact parameters of order of $\mathrm{c}\langle\mathrm{t}\rangle \sim 300 \mu \mathrm{~m}$
- need a detector with resolution one order of magnitude better to detect them with high efficiency and purity.
- In ATLAS ( $\mathrm{B}=2 \mathrm{~T}, \mathrm{~L}=1 \mathrm{~m}$ ) a 200 GeV particle has a sagitta of about $400 \mu \mathrm{~m}$.
- to be able to reconstruct accurately new high energy resonances the sagitta should be reconstructed with few tens of $\mu \mathrm{m}$ precision.


## THE DETECTORS

## Semiconductor detectors

- Semiconductor detectors consists of inversely polarized p-n junctions.
- Depleted region with only static charge density $\mathrm{N}_{\mathrm{D}}-\mathrm{N}_{\mathrm{A}}$
- thickness $W=\sqrt{\mu \rho \varepsilon\left(V_{\text {bias }}+V_{\mathrm{BI}}\right)}$
$\mu=$ carrier mobility $1350 \mathrm{~cm}^{2} \mathrm{~V}^{-1} \mathrm{~s}^{-1}$ for $\mathrm{e}, 450 \mathrm{~cm}^{2} \mathrm{~V}^{-1} \mathrm{~s}^{-1}$ for h
$\rho=$ resisitivity (detector grade Si is $1-10 \mathrm{k} \Omega / \mathrm{cm}$ )
$\varepsilon=$ dielectric constant, $11.9 \varepsilon_{0} \quad \mathrm{~V}_{\mathrm{BI}}=$ built-in voltage $\sim 0.5 \mathrm{~V}$
- When a charged particle crosses the detector:
- collisions excite electrons to the conduction band, creating electron-hole pairs ( $\sim 3.6 \mathrm{eV} /$ pair, $\sim 80$ pairs $/ \mu \mathrm{m}$ )
- the mobile carriers are separated by the junction electric field, generating a current signal of few ns length.



## Position sensitive detectors

- The first high resolution detectors were silicon microstrip.
- Use of microlithography from semiconductor electronics industry.
- Fine segmentation of collecting electrodes: $\mu \mathrm{m}$ level resolution
- Thickness of few hundreds $\mu \mathrm{m}$ : signal of $10^{4} \mathbf{e}-\mathrm{h}$, detectable with low noise electronics



## Various types of Si detectors

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## Pixel tecnologies

## Monolythics

## Three Phase CCD Clocking



CCD
Integrated readout Low pitch
Low mass
Relatively slow readout Radiation hardness

## DEPFET

DEpleted P-channel FET


Bump bonded readout front-end:

- more material
- pitch limited by electronics.
Fast
Rad-hard

Hybrids


Churgol Parlisit

## EXAMPLES OF SYSTEMS

## ALEPH@ LEP

- 2 planes Si microstrips $25 \mu \mathrm{~m}$ pitch
- Inner jet chamber
- Large volume Time Projection Chamber


## ALTPRH DALI



- $\quad$ Large vol


$-0.9 \mathrm{~cm}$


## ATLAS and CMS at LHC



- 3 pixel layers
- $50 \mu \mathrm{~m} \times 400 \mu \mathrm{~m}$
$-1.4 \mathrm{~m}^{2}$ of silicon
- 80 million pixels
- 3 pixel layers
- $100 \mu \mathrm{~m} \times 150 \mu \mathrm{~m}$
- 10 strip layers
- 80-183 $\mu \mathrm{m}$ pitch
- $200 \mathbf{~ m}^{2}$ of silicon
- >9 million strips
- $\mathrm{B}=4 \mathrm{~T}$

A. Andreazza - Silicon Tracking


## Resolution

The CMS experiment at the CERN LHC, JIST 3 (2008) S08004


## Material and efficiency

Material contributes not only to resolution, but also to efficiency:

- Si is almost $100 \%$ efficient
- Interactions may deviate the particles, splitting the track.




## LHCb

## LHCb tracking


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TRACK FITTING

## Track fitting: straight track model

- In our previous examples we used only the minimal number of points.
- Usually more measurements then the minimum:
- redundancy
- pattern recognition
- improved precision

- Simple straight line model: $y=a+b x$ expected crossing points: $y_{i}^{\prime}=a+b x_{i}$
- Best parameters are defined by minimizing the $\chi^{2}$ of the residuals between the measurements $\boldsymbol{y}_{\mathbf{i}}$ and the expectations $\boldsymbol{y}_{\mathbf{i}}^{\prime}$ from a set of parameters $(\boldsymbol{a}, \boldsymbol{b})$.
- If we neglet multiple scattering:

```
                                    inverse of
```

$\chi^{2} \quad \boldsymbol{\Gamma}\left(y_{i}-a-b x_{i}\right)^{2}=(\mathbf{Y}-\mathbf{A p})^{T} \mathbf{V}^{-1} \mathbf{Y}$ covariance matrix $\chi^{2}=\sum_{i=1,2,3} \frac{\left(y_{i}-a-b x_{i}\right)^{2}}{\sigma_{y_{i}}^{2}}=(\mathbf{Y}-\mathbf{A p}) \mathbf{V}^{-1}(\mathbf{Y}-\mathbf{A} \mathbf{p})$

$$
\mathbf{p}=\binom{a}{b} \quad \mathbf{Y}=\left(\begin{array}{l}
y_{1} \\
y_{2} \\
y_{3}
\end{array}\right) \quad \mathbf{A}=\left[\begin{array}{ll}
1 & x_{1} \\
1 & x_{2} \\
1 & x_{3}
\end{array}\right] \quad \mathbf{V}=\left[\begin{array}{ccc}
\sigma_{y_{1}}^{2} & 0 & 0 \\
0 & \sigma_{y_{2}}^{2} & 0 \\
0 & 0 & \sigma_{y_{3}}^{2}
\end{array}\right]
$$

## Track fitting: multiple scattering

- In reality $\boldsymbol{y}_{\mathrm{i}}-\boldsymbol{y}_{\mathrm{i}}^{\prime}$ contains contributions from multiple scattering:

$$
\begin{array}{l|l}
y_{1}=a+b x_{1}+\varepsilon_{1} & \begin{array}{l}
\varepsilon=\text { measurement error } \\
\delta \theta=\text { m.s. deflection }
\end{array} \\
y_{2}=a+b x_{2}+\varepsilon_{2}+\left(x_{2}-x_{1}\right) \delta \theta_{1} \\
y_{3}=a+b x_{3}+\varepsilon_{3}+\left(x_{3}-x_{1}\right) \delta \theta_{1}+\left(x_{3}-x_{2}\right) \delta \theta_{2}
\end{array}
$$



- The definition of the covariance matrix is: $V_{i j}=\left\langle\left(y_{i}-y_{i}^{\prime}\right)\left(y_{j}-y_{j}^{\prime}\right)\right\rangle$
- Uncertainties are $\left\langle\varepsilon_{i}^{2}\right\rangle=\sigma_{y_{i}}^{2},\left\langle\delta \theta_{i}^{2}\right\rangle=\theta_{\mathrm{ms}, i}^{2}$
- Error sources are not correlated: $\left\langle\varepsilon_{i} \varepsilon_{j}\right\rangle=0, i \neq j ; \quad\left\langle\delta \theta_{i} \delta \theta_{j}\right\rangle=0, i \neq j ; \quad\left\langle\varepsilon_{i} \delta \theta_{j}\right\rangle=0$
- Diagonal elements:

$$
\begin{aligned}
& V_{11}=\left\langle\varepsilon_{1}^{2}\right\rangle=\sigma_{y_{1}}^{2} \\
& V_{22}=\left\langle\left(\varepsilon_{2}+\left(x_{2}-x_{1}\right) \delta \theta_{1}\right)^{2}\right\rangle=\left\langle\varepsilon_{2}^{2}\right\rangle+2\left\langle\varepsilon_{2}\left(x_{2}-x_{1}\right) \delta \theta_{1}\right\rangle+\left\langle\left(x_{2}-x_{1}\right)^{2} \delta \theta_{1}^{2}\right\rangle=\sigma_{y_{2}}^{2}+\left(x_{2}-x_{1}\right)^{2} \theta_{\mathrm{ms}, 1}^{2} \\
& V_{33}=\sigma_{y_{3}}^{2}+\left(x_{3}-x_{1}\right)^{2} \theta_{\mathrm{ms}, 1}^{2}+\left(x_{3}-x_{2}\right)^{2} \theta_{\mathrm{ms}, 2}^{2}
\end{aligned}
$$

## Track fitting: multiple scattering

- In reality $\boldsymbol{y}_{\mathrm{i}}-\boldsymbol{y}_{\mathrm{i}}^{\prime}$ contains contributions from multiple scattering:

$$
\begin{array}{l|l}
y_{1}=a+b x_{1}+\varepsilon_{1} & \begin{array}{l}
\varepsilon=\text { measurement error } \\
\delta \boldsymbol{\theta}=\text { m.s. deflection }
\end{array} \\
y_{2}=a+b x_{2}+\varepsilon_{2}+\left(x_{2}-x_{1}\right) \delta \theta_{1} \\
y_{3}=a+b x_{3}+\varepsilon_{3}+\left(x_{3}-x_{1}\right) \delta \theta_{1}+\left(x_{3}-x_{2}\right) \delta \theta_{2}
\end{array}
$$



- The definition of the covariance matrix is: $V_{i j}=\left\langle\left(y_{i}-y_{i}^{\prime}\right)\left(y_{j}-y_{j}^{\prime}\right)\right\rangle$
- Uncertainties are $\left\langle\varepsilon_{i}^{2}\right\rangle=\sigma_{i}^{2},\left\langle\delta \theta_{i}^{2}\right\rangle=\theta_{\mathrm{ms}, i}^{2}$
- Error sources are not correlated: $\left\langle\varepsilon_{i} \varepsilon_{j}\right\rangle=0, i \neq j ; \quad\left\langle\delta \theta_{i} \delta \theta_{j}\right\rangle=0, i \neq j ; \quad\left\langle\varepsilon_{i} \delta \theta_{j}\right\rangle=0$
- Non-diagonal elements:

$$
\begin{aligned}
V_{12} & =V_{13}=0 \\
V_{23} & =\left\langle\left(\varepsilon_{2}+\left(x_{2}-x_{1}\right) \delta \theta_{1}\right)\left(\varepsilon_{3}+\left(x_{3}-x_{1}\right) \delta \theta_{1}+\left(x_{3}-x_{2}\right) \delta \theta_{2}\right)\right\rangle=\left\langle\left(x_{2}-x_{1}\right)\left(x_{3}-x_{1}\right) \delta \theta_{1}^{2}\right\rangle \\
& =\left(x_{2}-x_{1}\right)\left(x_{3}-x_{1}\right) \theta_{\mathrm{ms}, 1}^{2}
\end{aligned}
$$

## Track fitting: multiple scattering

- Finally, the covariance V to be used in the $\chi^{2}$ minimization is:è

$$
\mathbf{V}=\left[\begin{array}{ccc}
\sigma_{y_{1}}^{2} & 0 & 0 \\
0 & \sigma_{y_{2}}^{2} & 0 \\
0 & 0 & \sigma_{y_{3}}^{2}
\end{array}\right]+\left[\begin{array}{ccc}
0 & 0 & 0 \\
0 & \left(x_{2}-x_{1}\right)^{2} \theta_{\mathrm{ms}, 1}^{2} & \left(x_{3}-x_{1}\right)\left(x_{2}-x_{1}\right) \theta_{\mathrm{ms}, 1}^{2} \\
0 & \left(x_{3}-x_{1}\right)\left(x_{2}-x_{1}\right) \theta_{\mathrm{ms}, 1}^{2} & \left(x_{3}-x_{1}\right)^{2} \theta_{\mathrm{ms}, 1}^{2}+\left(x_{3}-x_{2}\right)^{2} \theta_{\mathrm{ms}, 2}^{2}
\end{array}\right]
$$

- The second matrix has:
- diagonal elements due to any previous material affecting the trajectory at a given plane.
- off-diagonal elements: present if a previous material layer affect the trajectory in more than one plane.
- In our case:
- scattering on plane 1
- affects the position in both plane 2 and plane 3



## Global $x^{2}$

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- The technique described till now consists in the minimization of a $\chi^{2}$ involving all measurement points:

$$
\chi^{2}=(\mathbf{Y}-\mathbf{A p})^{T} \mathbf{V}^{-1}(\mathbf{Y}-\mathbf{A p})
$$

and therefore is indicated as a global $\boldsymbol{\chi}^{\mathbf{2}}$ :

- requires the inversion of a NxN covariance matrix ( $\mathrm{N}=$ number of measurements)
- has become popular with silicon tracking systems because tracks have few, precise measurements
- Our model assumes the whole track is a straight line:
- $b$ is sort average track direction
- but we are interested in track direction at the production point
- Multiple scattering is taken into account by giving lower weights to points far away from the interaction region

How can it be improved?

## Global $x^{2}$

- Insert scattering angles as part of the track model

track direction changes along $x$
- Additional parameters, with expectation value 0 and r.m.s. $\theta_{\text {ms }}$
- The same $\chi^{2}=(\mathbf{Y}-\mathbf{A p})^{T} \mathbf{V}^{-1}(\mathbf{Y}-\mathbf{A p})$ holds, but with the modified matrices:
$\begin{aligned} & \mathbf{p}=\left(\begin{array}{c}a \\ b \\ \delta \theta_{1} \\ \delta \theta_{2}\end{array}\right) \quad \mathbf{Y}=\left(\begin{array}{c}y_{1} \\ y_{2} \\ y_{3} \\ 0 \\ 0\end{array}\right) \quad \mathbf{A}=\left[\begin{array}{cccc}1 & x_{1} & 0 & 0 \\ 1 & x_{2} & x_{2}-x_{1} & 0 \\ 1 & x_{3} & x_{3}-x_{1} & x_{3}-x_{2} \\ 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & 1\end{array}\right] \quad \mathbf{V}=\left[\begin{array}{ccccc}\sigma_{y_{1}}^{2} & 0 & 0 & 0 & 0 \\ 0 & \sigma_{y_{2}}^{2} & 0 & 0 & 0 \\ 0 & 0 & \sigma_{y_{3}}^{2} & 0 & 0 \\ 0 & 0 & 0 & \theta_{\mathrm{ms}, 1}^{2} & 0 \\ 0 & 0 & 0 & 0 & \theta_{\mathrm{ms}, 2}^{2}\end{array}\right] \\ &- \text { The number of degrees of freedom does not change }\end{aligned}$
- Estimate multiple scattering instead of putting it into the weights
- Step-by-step updating procedure:
- use initial estimation of track parameters
- extrapolate to next measured point
- compare extrapolation with measurement
- derive updated track parameters
- Continue adding all points one at the time.
- For each point invert a matrix of size equal to the track parameters
- computation time is $\mathrm{Nd}^{3}$ instead of $\mathrm{N}^{3}$
- Comparison allows for rejection of outliers
- can also be used during pattern recognition

production vertex
- Only providing basic idea of Kalman filtering
- one iteration of the fit, from detector plane $k-1$ to $k$
- see bibliography for more details
- At plane $k-1$ we have an estimation of the track parameters $\mathbf{p}_{k-1}$, with their covariance matrix $\mathbf{C}_{k-1}$.
- Extrapolate to plane $k$ :

$$
\begin{array}{ll}
\tilde{\mathbf{p}}_{k}=\mathbf{f}\left(\mathbf{p}_{k-1}\right) \\
\tilde{\mathbf{C}}_{k}=\mathbf{F C}_{k} \mathbf{F}^{\mathrm{T}}+\mathbf{M}_{m s} & \mathbf{F}=\frac{\partial \mathbf{f}}{\partial \mathbf{p}}\left(\mathbf{p}_{k-1}\right)
\end{array}
$$

- $\mathbf{M}_{m s}$ includes the multiple scattering uncertainty in the extrapolation.
- On surface $k$ we have some measurements $\mathbf{m}_{k}$ with covariance $\mathbf{V}_{k}$.

- The updated parameters $\mathbf{p}_{k}$ are obtained my minimizing a $\chi^{2}$ including:
- comparison of $\mathbf{m}_{k}$ with expectations $\mathbf{y}_{k}\left(\mathbf{p}_{k}\right)$ from the track model
- the extrapolated parameters

$$
\begin{aligned}
\chi^{2}= & \left(\mathbf{m}_{k}-\mathbf{y}_{k}\left(\mathbf{p}_{k}\right)\right)^{\mathrm{T}} \mathbf{V}_{k}^{-1}\left(\mathbf{m}_{k}-\mathbf{y}_{k}\left(\mathbf{p}_{k}\right)\right) \\
& +\left(\tilde{\mathbf{p}}_{k}-\mathbf{p}_{k}\right)^{\mathrm{T}} \tilde{\mathbf{C}}_{k}^{-1}\left(\tilde{\mathbf{p}}_{k}-\mathbf{p}_{k}\right)
\end{aligned}
$$

- Try to develop the concrete expressions for a linear track fit:
- solutions in the back-up slides


## APPLICATIONS

## Invariant mass reconstruction



## Higgs and momentum resolution



Future experiments at the ILC can perform a measurement of the total production rate from mass of the system recoiling agaist the Z

Separation of the Higgs signal in the $\mathrm{H} \rightarrow \mathrm{ZZ}$ decay at the LHC rely on accurate curvature determination.

## Identification of short lived particles

Istituto Nazionale
di Fisica Nucleare

quark b $\sim 1.5 \mathrm{ps}$
quark c $\sim 0.5 \mathrm{ps}$
$\tau$ lepton 0.29 ps

Decay length:

$$
\sim \gamma \beta \mathrm{ct}
$$

Impact parameter:
$\sim \mathbf{c} \tau$
A. Andreazza - Silicon Tracking


## $\mathrm{B}_{\mathrm{o}}^{0}$ oscillations



## $\mathrm{Z} \rightarrow \tau \tau \rightarrow \mu \mu+4 v$



## Conclusions

- I hope to have provided you with a quick overview of the very basics of charged particle tracking:
- how it works
- why it is useful
- ...and why Si detectors are great at that!
- Many topics not addressed here:
- detector technologies just shortly listed
- front-end electronics and position reconstruction (beyond just electrode segmentation)
- no mention of radiation damage
- pattern recognition and vertex reconstruction
- future intelligent trigger systems


## All of these are very active and challenging research areas

## Example

## KALMAN FILTER FOR

 "STRAIGHT" TRACKS- Initial estimate of track parameters using $j, k$

$$
\begin{aligned}
& y=a_{j}+b_{j}\left(z-z_{j}\right) \\
& \mathbf{p}_{j}=\binom{a_{j}}{b_{j}}=\binom{y_{j}}{\frac{y_{k}-y_{j}}{z_{k}-z_{j}}} \quad \mathbf{C}_{j}=\left(\begin{array}{cc}
\sigma_{y_{j}}^{2} & -\frac{\sigma_{y_{j}}^{2}}{z_{k}-z_{j}} \\
-\frac{\sigma_{y_{j}}^{2}}{z_{k}-z_{j}} & \frac{\sigma_{y_{j}}^{2}+\sigma_{y_{k}}^{2}}{\left(z_{k}-z_{j}\right)^{2}}
\end{array}\right)
\end{aligned}
$$



- Extrapolate to point $i$ :

$$
y=a_{j}+b_{j}\left(z-z_{j}\right) \Rightarrow y=a_{i}+b_{i}\left(z-z_{i}\right)
$$

$$
\widetilde{\mathbf{p}}_{i}=\binom{\widetilde{a}_{i}}{\widetilde{b}_{i}}=\binom{a_{j}-b_{j}\left(z_{j}-z_{i}\right)}{b_{j}}
$$

$$
\widetilde{\mathbf{C}}_{j}=\frac{1}{\left(z_{k}-z_{j}\right)^{2}}\left(\begin{array}{cc}
\left(z_{k}-z_{i}\right)^{2} \sigma_{y_{j}}^{2}+\left(z_{j}-z_{i}\right)^{2} \sigma_{y_{k}}^{2} & -\left(z_{k}-z_{i}\right) \sigma_{y_{j}}^{2}-\left(z_{j}-z_{i}\right) \sigma_{y_{k}}^{2} \\
-\left(z_{k}-z_{i}\right) \sigma_{y_{j}}^{2}-\left(z_{j}-z_{i}\right) \sigma_{y_{k}}^{2} & \sigma_{y_{j}}^{2}+\sigma_{y_{k}}^{2}
\end{array}\right)+\theta_{p, j}^{2}\left(\begin{array}{cc}
\left(z_{j}-z_{i}\right)^{2} & z_{j}-z_{i} \\
z_{j}-z_{i} & 1
\end{array}\right)
$$

which gives contribution to the $\chi^{2}$ for the parameters at $i$ :

$$
\mathbf{p}_{i}=\binom{a_{i}}{b_{i}}
$$

$$
\chi^{2}=\left(\widetilde{\mathbf{p}}_{i}-\mathbf{p}_{i}\right)^{T} \widetilde{\mathbf{C}}^{-1}\left(\widetilde{\mathbf{p}}_{i}-\mathbf{p}_{i}\right)
$$

- The measurement at $i$ gives the term:

$$
\begin{aligned}
& y=a_{i}+b_{i}\left(z-z_{i}\right) \\
& \mathbf{H}_{i}=\left(\begin{array}{ll}
1 & 0
\end{array}\right) \mathbf{H}_{i} \mathbf{p}_{j}-y_{i}=a_{i}-y_{i} \\
& \chi^{2}=\frac{\left(y_{i}-a_{i}\right)^{2}}{\sigma_{y_{i}}^{2}}
\end{aligned}
$$

- And the new parameters are obtained by the minimization of:

$$
\chi^{2}=\left(\widetilde{\mathbf{p}}_{i}-\mathbf{p}_{i}\right)^{T} \widetilde{\mathbf{C}}^{-1}\left(\widetilde{\mathbf{p}}_{i}-\mathbf{p}_{i}\right)+\frac{\left(y_{i}-a_{i}\right)^{2}}{\sigma_{y_{i}}^{2}}
$$

- Which can be put in the general $\chi^{2}$ form: $\chi^{2}=(\mathbf{Y}-\mathbf{A p})^{T} \mathbf{V}^{-1}(\mathbf{Y}-\mathbf{A p})$

$$
\mathbf{p}=\binom{a_{i}}{b_{i}} \quad \mathbf{Y}=\left(\begin{array}{l}
\widetilde{a}_{i} \\
\widetilde{b}_{i} \\
y_{i}
\end{array}\right) \quad \mathbf{A}=\left[\begin{array}{ll}
1 & 0 \\
0 & 1 \\
1 & 0
\end{array}\right] \quad \mathbf{V}=\left[\begin{array}{cc}
\widetilde{\mathbf{C}}_{i} & \mathbf{0} \\
\mathbf{0} & \sigma_{y_{i}}^{2}
\end{array}\right]
$$

$$
\begin{aligned}
& \text { whose solution is: } \\
& \mathbf{p}=\left(\mathbf{A}^{T} \mathbf{W} \mathbf{A}\right)^{-1} \mathbf{A}^{T} \mathbf{W} \mathbf{Y} \\
& \mathbf{C}_{i}=\left(\mathbf{A}^{T} \mathbf{W} \mathbf{A}\right)^{-1} \quad \mathbf{W}=\mathbf{V}^{-1}=\left[\begin{array}{cc}
\tilde{\mathbf{C}}_{i}^{-1} & \mathbf{0} \\
\mathbf{0} & 1 / \sigma_{y_{i}}^{2}
\end{array}\right]
\end{aligned}
$$

## Kalman filter: example

## - And finally, going to the interaction point:

$$
y=a_{0}+b_{0} z
$$

$$
\mathbf{p}_{0}=\binom{a_{0}}{b_{0}}=\binom{a_{i}-b_{i} z_{i}}{b_{i}}
$$

$$
\mathbf{C}_{0}=\left(\begin{array}{cc}
1 & -z_{i} \\
0 & 1
\end{array}\right) \mathbf{C}_{i}\left(\begin{array}{cc}
1 & 0 \\
-z_{i} & 1
\end{array}\right)+\theta_{p, i}^{2}\left(\begin{array}{cc}
z_{i}^{2} & -z_{i} \\
-z_{i} & 1
\end{array}\right)
$$



